

<b>Notice of References Cited</b>		Application/Control No. 10/580,401	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner MEWALE AMBAYE	Art Unit 2472	Page 1 of 1

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*	B	US-2003/0084089	05-2003	Kurose et al.	709/200
*	C	US-7,215,640	05-2007	Matsubara, Daisuke	370/235
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	M	US-			

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